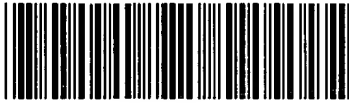


Search Notes

Application/Control No.

09/673,422

Examiner

Christopher A. Revak

Applicant(s)/Patent under
Reexamination

TAKECHI ET AL.

Art Unit

2131

SEARCHED

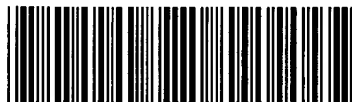
Class	Subclass	Date	Examiner
713	158,194	9/12/2006	CR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
709	217,229	4/2/2004	CR
382	100	4/2/2004	CR
705	52,54,59	4/2/2004	CR
713/155,165,175,176, 190,193,200		4/2/2004	CR

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS Text Search USPAT, US PG PUB, USOCR, DERWENT, IBM TDB, FPRS, EPO, JPO	9/12/2006	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	9/12/2006	CR

Search Notes (continued)

Application/Control No.

09/673,422

Examiner

Christopher A. Revak

Applicant(s)/Patent under
Reexamination

TAKECHI ET AL.

Art Unit

2131

SEARCHED

Class	Subclass	Date	Examiner
none	none	9/12/2006	CR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
163	29	4/2/2004	CR
725	29	4/2/2004	CR
713	158,194	9/12/2006	CR
380/28,100,242,255,283		4/2/2004	CR

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
n/a		